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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

May 7, 2003

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to the: Commissioner for Patents, Alexandria, VA 22313-1450 on:

By:

Deborah Celeste

Date

TRANSMITTAL OF REVOCATION AND GRANT OF POWER OF ATTORNEY

Sir:

Enclosed for filing are three Revocations and Grants of Power Attorney to be entered in each application identified on Appendix A as attached to each Power of Attorney.

Respectfully submitted,

By:

Maria Eliseeva

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
REVOCATION AND GRANT OF POWER OF ATTORNEY

Docket No. 21295

Serial No.: See Appendix A
Name of Assignee: Leica Microsystems
Address: AM Friedensplatz 3
D-68165 Mannheim
Germany

TO THE ASSISTANT COMMISSIONER FOR PATENTS

Honorable Sir:

I hereby state that I am authorized to act on behalf of the assignee, Leica Microsystems, as Director of Corporate Patents Trademark Dept. and state that it is the assignee of the entire right, title, and interest of all patent applications listed in the attached Appendix A.

I hereby appoint:

Maria M. Eliseeva Reg. No. 43,328
J. Grant Houston Reg. No. 35,900

under Customer No. 29127 and of the firm:

Houston Eliseeva
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as attorneys to prosecute the applications as listed on Appendix A, to transact all business in the U.S. Patent and Trademark Office and any other Industrial Property protection office in any other country connected with all patent applications as listed on Appendix A. Applicant hereby revokes all other previous powers of attorney associated with the applications as listed on Appendix A.

Please direct all future correspondence to the principal attorney of record as:

Maria M. Eliseeva
Houston Eliseeva
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Leica Microsystems

By:


Dr. Werner Reichert, Director
Corporate Patents Trademark Dept.

Dated:

May 10 / 03

APPENDIX A

<u>Title</u>	<u>Serial/Patent Number</u>	<u>Filing/Issue Date</u>	<u>Assignment Recorded Reel/Frame</u>
Method and System for Compensating Intensity Fluctuations of an Illumination System in a Confocal Microscope	09/476,649 6,444,971	December 31, 1999 September 3, 2002	May 2, 2000 010792/0814
Apparatus for Changing Objective Lenses In a Microscope	09/678,129 6,525,876	October 4, 2000 February 25, 2003	Jan. 26, 2001 011473/0806
Apparatus for Optical Scanning of Multiple Specimens	09/681,008	November 15, 2000	Jan. 19, 2001 011455/0504
Apparatus for Beam Deflection	09/681,014	November 20, 2000	May 10, 2001 011792/0248
Method for Optical – Light Scanning of A Specimen; and Scanning Microscope For Scanning a Specimen	09/681,019	November 28, 2000	Feb. 28, 2001 011555/0780
Method and Apparatus for Measuring Thickness of Transparent Film	09/708,778 6,545,765	November 8, 2000 April 8, 2003	June 4, 2001 011863/0987
Microscope and Method for Analyzing Acquired Scan Data	09/681,051	December 10, 2000	May 10, 2001 011792/0203
Method and System for Processing Scan-Data from a Confocal Microscope	09/476,589 6,423,960	December 31, 1999 July 23, 2002	Dec. 31, 1999 010496/0608

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<u>Title</u>	<u>Serial/Patent Number</u>	<u>Filing/Issue Date</u>	<u>Assignment Recorded Reel/Frame</u>
Arrangement for Detecting Fluorescent Light from a Plurality of Sample Points	09/856,414	May 18, 2001	May 18, 2001 011936/0907
Arrangement for Detecting Fluorescent Light from a Plurality of Sample Points	09/681,109	January 10, 2001	April 4, 2001 011690/0739
Method for Examining Structures on a Semiconductor Substrate	09/681,186	February 14, 2001	June 14, 2001 011896/0263
Apparatus for Combining Light and Confocal Scanning Microscope	09/825,273	April 3, 2001	May 10, 2001 011789/0149
Double Confocal Scanning Microscope	09/826,712	April 5, 2001	April 5, 2001 011693/0809
Displaceable X/Y Coordinate Measurement Table	09/464,559 6,347,458	December 16, 1999 February 19, 2002	Dec. 16, 1999 010467/0347
Method and System for User Guidance in Scanning Microscopy	09/476,588	December 31, 1999	April 10, 2000 010735/0303
Method and System for User Guidance in Scanning Microscopy	10/379,162	March 3, 2003	April 10, 2000 010735/0303

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<u>Title</u>	<u>Serial/Patent Number</u>	<u>Filing/Issue Date</u>	<u>Assignment Recorded Reel/Frame</u>
Measuring Instrument and Method for Measuring Features on a Substrate	09/681,096	January 4, 2001	Feb. 13, 2001 011525/0354
Apparatus for Objective Changing and Microscope Having an Apparatus for Objective Changing	09/681,918	June 26, 2001	June 26, 2001 011690/0822
Optical Arrangement for Selection and Detection of the Spectral Region of a Light Beam and Confocal Scanning Microscope	09/682,187	August 2, 2001	Jan. 17, 2002 012482/0855
Method and Arrangement for Controlling Analytical and Adjustment Operations of a Microscope, and Software Program	09/682,329	August 21, 2001	Jan. 15, 2002 012480/0412
Double Confocal Scanning Microscope	09/683,713	February 6, 2002	Feb. 6, 2002 012367/0415
Method and Arrangement For Imaging and Measuring Three- Dimensional Structures	09/683,795	February 15, 2002	Feb. 15, 2002 012397/0082

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<u>Title</u>	<u>Serial/Patent Number</u>	<u>Filing/Issue Date</u>	<u>Assignment Recorded Reel/Frame</u>
Method for Adjusting a Microscope and Microscope with a Device for Adjusting a Light Beam	09/683,824	February 20, 2002	Feb. 20, 2002 012405/0372
Method and Device for Adjusting at Least One Light Beam in an Optical System	10/098,016	March 13, 2002	March 29, 2002 012534/0626
Illumination Device and Illumination Method for a Scanning Microscope	10/064,653	August 2, 2002	August 27, 2002 013025/0866
Analytical Measuring and Evaluation Method for Molecular Interactions	10/203,169	August 7, 2002	March 4, 2003 013452/0304
Method for Time-Optimized Acquisition of Special Spectra Using a Scanning Microscope	10/249,181	March 20, 2003	March 20, 2003 013494/0315